intersil™

DATASHEET

Radiation Hardened CMOS Dual SPDT Analog Switch

HS-303ARH, HS-303AEH, HS-303BRH, HS-303BEH

The HS-303ARH, HS-303AEH, HS-303BRH, HS-303BEH analog switches are monolithic devices fabricated using Intersil's dielectrically isolated Radiation Hardened Silicon Gate (RSG) process technology to insure latch-up free operation. They are pinout compatible and functionally equivalent to the HS-303RH, but offer improved 300kRAD(Si) total dose capability. These switches offers low-resistance switching performance for analog voltages up to the supply rails. ON-resistance is low and stays reasonably constant over the full range of operating voltage and current. ON-resistance also stays reasonably constant when exposed to radiation. Break-before-make switching is controlled by 5V digital inputs. The HS-303ARH, HS-303AEH should be operated with nominal ±15V supplies, while the HS-303BRH, HS-303BEH should be operated with nominal ±12V supplies.

Specifications

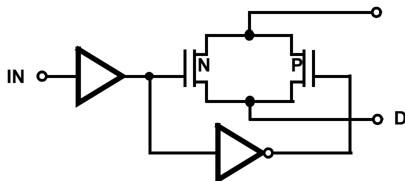
Specifications for Rad Hard QML devices are controlled by the Defense Logistics Agency Land and Maritime (DLA). The SMD number listed in the following must be used when ordering.

Detailed Electrical Specifications for the HS-303ARH, HS-303AEH, HS-303BRH, HS-303BEH are contained in SMD 5962-95813.

Features

- QML, per MIL-PRF-38535
- Radiation performance
  - Total dose: $3x10^5$ rad(Si)
  - SEE: For LET = 60MeV-mg/cm^2 at 60° incident angle, <150pC charge transferred to the output of an off switch
- No latch-up, dielectrically isolated device islands
- Pinout and functionally compatible with Intersil HS-303RH and HI-303 series analog switches
- Analog signal range equal to the supply voltage range
- Low leakage . . . . 100nA (max, post-rad)
- Low r_{ON} . . . . 70Ω (max, post-rad)
- Low standby supply current . . . . +150µA/-100µA (max, post-rad)

Functional Diagram

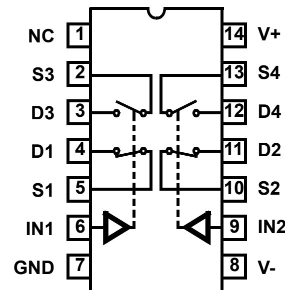


TRUTH TABLE

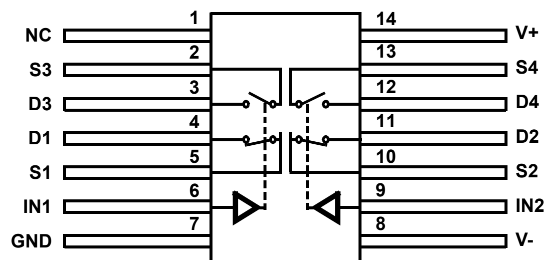
LOGIC	SW1 AND SW2	SW3 AND SW4
0	OFF	ON
1	ON	OFF

Pin Configurations

HS1-303ARH, HS-303BRH (SBDIP), CDIP2-T14 TOP VIEW



HS-303ARH, HS-303AEH, HS-303BRH, HS-303BEH (FLATPACK) CDFP3-F14 TOP VIEW



CAUTION: These devices are sensitive to electrostatic discharge; follow proper IC Handling Procedures.
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Ordering Information

ORDERING NUMBER (Note 2)	PART NUMBER (Note 1)	TEMP. RANGE (°C)	PACKAGE (RoHS Compliant)	PKG. DWG. #
5962F9581304QCC	HS1-303ARH-8	-55 to +125	14 LD SBDIP	D14.3
5962F9581304QXC	HS9-303ARH-8	-55 to +125	14 LD Flatpack	K14.A
5962F9581304V9A	HS0-303ARH-Q	-55 to +125	Die	D14.3
5962F9581306V9A	HS0-303AEH-Q	-55 to +125	Die	D14.3
5962F9581304VCC	HS1-303ARH-Q	-55 to +125	14 LD SBDIP	D14.3
5962F9581306VCC	HS1-303AEH-Q	-55 to +125	14 LD SBDIP	D14.3
5962F9581304VXC	HS9-303ARH-Q	-55 to +125	14 LD Flatpack	K14.A
HS0-303ARH/SAMPLE	HS0-303ARH/SAMPLE	-55 to +125	Die	
HS1-303ARH/PROTO	HS1-303ARH/PROTO	-55 to +125	14 LD SBDIP	D14.3
HS9-303ARH/PROTO	HS9-303ARH/PROTO	-55 to +125	14 LD Flatpack	K14.A
5962F9581306VXC	HS9-303AEH-Q	-55 to +125	14 LD Flatpack	K14.A
5962F9581305QCC	HS1-303BRH-8	-55 to +125	14 LD SBDIP	D14.3
5962F9581305QXC	HS9-303BRH-8	-55 to +125	14 LD Flatpack	K14.A
5962F9581305V9A	HS0-303BRH-Q	-55 to +125	Die	D14.3
5962F9581307V9A	HS0-303BEH-Q	-55 to +125	Die	D14.3
5962F9581305VCC	HS1-303BRH-Q	-55 to +125	14 LD SBDIP	D14.3
5962F9581307VCC	HS1-303BEH-Q	-55 to +125	14 LD SBDIP	D14.3
5962F9581305VXC	HS9-303BRH-Q	-55 to +125	14 LD Flatpack	K14.A
HS0-303BRH/SAMPLE	HS0-303BRH/SAMPLE	-55 to +125	Die	
HS1-303BRH/PROTO	HS1-303BRH/PROTO	-55 to +125	14 LD SBDIP	D14.3
HS9-303BRH/PROTO	HS9-303BRH/PROTO	-55 to +125	14 LD Flatpack	K14.A
5962F9581307VXC	HS9-303BEH-Q	-55 to +125	14 LD Flatpack	K14.A

NOTES:

1. These Intersil Pb-free Hermetic packaged products employ 100% Au plate - e4 termination finish, which is RoHS compliant and compatible with both SnPb and Pb-free soldering operations.
2. Specifications for Rad Hard QML devices are controlled by the Defense Logistics Agency Land and Maritime (DLA). The SMD numbers listed in the "Ordering Information" table must be used when ordering.

Die Characteristics

DIE DIMENSIONS:

2690µm x 5200µm (106mils x 205mils)
Thickness: 483µm ± 25.4µm (19mils ± 1mil)

INTERFACE MATERIALS:

Glassivation:

Type: PSG (Phosphorous Silicon Glass)
Thickness: 8.0kÅ ± 1.0kÅ

Top Metallization:

Type: AlSiCu
Thickness: 16.0kÅ ± 2kÅ

Substrate:

Radiation Hardened Silicon Gate,
Dielectric Isolation

Backside Finish:

Silicon

ASSEMBLY RELATED INFORMATION:

Substrate Potential:

Unbiased (DI)

ADDITIONAL INFORMATION:

Worst Case Current Density:

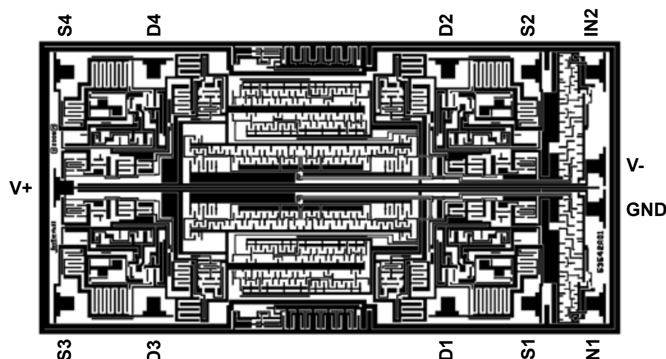
$<2.0 \times 10^5$ A/cm^2

Transistor Count:

332

Metallization Mask Layout

HS-303ARH, HS-303AEH, HS-303BRH, HS-303BEH



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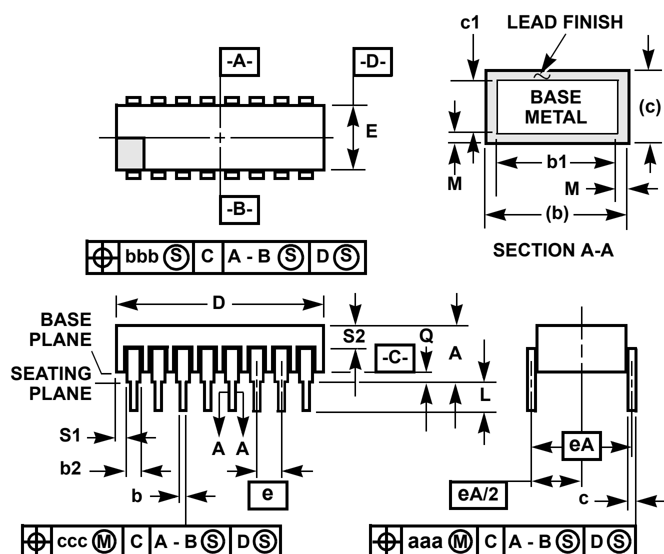
Ceramic Dual-In-Line Metal Seal Packages (SBDIP)



NOTES:

1. Index area: A notch or a pin one identification mark shall be located adjacent to pin one and shall be located within the shaded area shown. The manufacturer's identification shall not be used as a pin one identification mark.
2. The maximum limits of lead dimensions b and c or M shall be measured at the centroid of the finished lead surfaces, when solder dip or tin plate lead finish is applied.
3. Dimensions b1 and c1 apply to lead base metal only. Dimension M applies to lead plating and finish thickness.
4. Corner leads (1, N, N/2, and N/2+1) may be configured with a partial lead paddle. For this configuration dimension b3 replaces dimension b2.
5. Dimension Q shall be measured from the seating plane to the base plane.
6. Measure dimension S1 at all four corners.
7. Measure dimension S2 from the top of the ceramic body to the nearest metallization or lead.
8. N is the maximum number of terminal positions.
9. Braze fillets shall be concave.
10. Dimensioning and tolerancing per ANSI Y14.5M - 1982.
11. Controlling dimension: INCH.

D14.3 MIL-STD-1835 CDIP2-T14 (D-1, CONFIGURATION C)

14 LEAD CERAMIC DUAL-IN-LINE METAL SEAL PACKAGE

SYMBOL	INCHES		MILLIMETERS		NOTES
	MIN	MAX	MIN	MAX	
A	-	0.200	-	5.08	-
b	0.014	0.026	0.36	0.66	2
b1	0.014	0.023	0.36	0.58	3
b2	0.045	0.065	1.14	1.65	-
b3	0.023	0.045	0.58	1.14	4
c	0.008	0.018	0.20	0.46	2
c1	0.008	0.015	0.20	0.38	3
D	-	0.785	-	19.94	-
E	0.220	0.310	5.59	7.87	-
e	0.100 BSC		2.54 BSC		-
eA	0.300 BSC		7.62 BSC		-
eA/2	0.150 BSC		3.81 BSC		-
L	0.125	0.200	3.18	5.08	-
Q	0.015	0.060	0.38	1.52	5
S1	0.005	-	0.13	-	6
S2	0.005	-	0.13	-	7
α	90°	105°	90°	105°	-
aaa	-	0.015	-	0.38	-
bbb	-	0.030	-	0.76	-
ccc	-	0.010	-	0.25	-
M	-	0.0015	-	0.038	2
N	14		14		8

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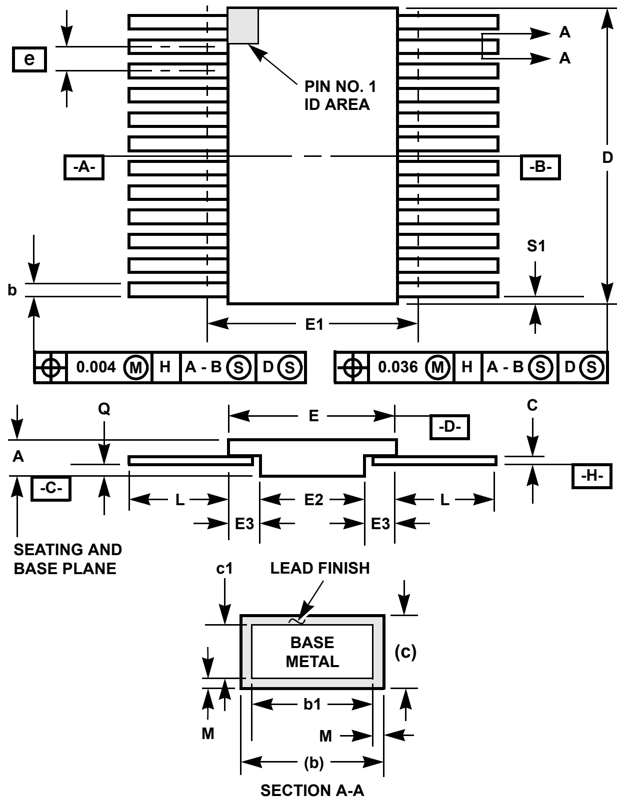
Ceramic Metal Seal Flatpack Packages (Flatpack)



K14.A MIL-STD-1835 CDFP3-F14 (F-2A, CONFIGURATION B)
14 LEAD CERAMIC METAL SEAL FLATPACK PACKAGE

SYMBOL	INCHES		MILLIMETERS		NOTES
	MIN	MAX	MIN	MAX	
A	0.045	0.115	1.14	2.92	-
b	0.015	0.022	0.38	0.56	-
b1	0.015	0.019	0.38	0.48	-
c	0.004	0.009	0.10	0.23	-
c1	0.004	0.006	0.10	0.15	-
D	-	0.390	-	9.91	3
E	0.235	0.260	5.97	6.60	-
E1	-	0.290	-	7.11	3
E2	0.125	-	3.18	-	-
E3	0.030	-	0.76	-	7
e	0.050 BSC		1.27 BSC		-
k	0.008	0.015	0.20	0.38	2
L	0.270	0.370	6.86	9.40	-
Q	0.026	0.045	0.66	1.14	8
S1	0.005	-	0.13	-	6
M	-	0.0015	-	0.04	-
N	14		14		-

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NOTES:

1. Index area: A notch or a pin one identification mark shall be located adjacent to pin one and shall be located within the shaded area shown. The manufacturer's identification shall not be used as a pin one identification mark. Alternately, a tab (dimension k) may be used to identify pin one.
2. If a pin one identification mark is used in addition to a tab, the limits of dimension k do not apply.
3. This dimension allows for off-center lid, meniscus, and glass overrun.
4. Dimensions b1 and c1 apply to lead base metal only. Dimension M applies to lead plating and finish thickness. The maximum limits of lead dimensions b and c or M shall be measured at the centroid of the finished lead surfaces, when solder dip or tin plate lead finish is applied.
5. N is the maximum number of terminal positions.
6. Measure dimension S1 at all four corners.
7. For bottom-brazed lead packages, no organic or polymeric materials shall be molded to the bottom of the package to cover the leads.
8. Dimension Q shall be measured at the point of exit (beyond the meniscus) of the lead from the body. Dimension Q minimum shall be reduced by 0.0015 inch (0.038mm) maximum when solder dip lead finish is applied.
9. Dimensioning and tolerancing per ANSI Y14.5M - 1982.
10. Controlling dimension: INCH.